Application/Control No. Applicant(s)/Patent Under Reexamination 10/666,765 IYER, MAHESH ANANTHARAMA Notice of References Cited Examiner Art Unit Page 1 of 1 Joseph P. Hirl 2129 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α US-В С US-D US-US-Ε US-F G US-Н US-

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	z					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*	<u> </u>	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U	A. Chandra et al, AVPGEN - A Test Generator for Architecture Verification, 1995, IEEE, 1063-8210/95, 188-200					
	V						
	w						
	×						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

US-

US-

US-US-

US-

ı

J K

М